U. S. PATENT DOCUMENTS

*EXAM INITI	1		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
CT	7	AA	5,531,685	7/96	Hemmer et al.		/	
1		AB	6,475,217	11/02	Platt		1	
		AC	6,425,894	7/02	Brucker et al.			
		AD	6,522,930	2/03	Schaer et al.			
		ΑE	5,938,694	8/99	Jaraczewski et al.			
		AF	5,800,482	9/98	Pomeranz et al.		X	
	-	AG	5,913,854	6/99	Maguire et al.		/	
		АН	5,919,188	7/99	Shearon et al.			
		Al	6,015,407	1/00	Reib et al.			
		AJ	6,083,222	7/00	Klein et al.	1/		
*		AK	6,113,556	9/00	Avitall		\	\

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		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	TRANSL	ATION
							YES	NO
CTN	AM	EP 0 856 292 A1	5/8/98	EPO				
1	AN	EP 0928 601 A1	14/07/99	EPO				
	AO	WO 94/02077	3/02/94	PCT		X		
1	AP	WO 99/56812	11/11/99	PCT				
	AQ							

OTHER REFERENCES (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

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LIST OF REFERENCES CITED BY APPLICANT

Dale Nelson et al.

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9/8/03

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
CTN	AA	6,212,434	4/01	Scheiner et al.			
CTN	AB	6,224,587	5/01	Gibson			
	AC						
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	AG						
	AH						
	Al						
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·	AK						

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